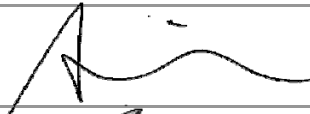




Product/Process Change Notification

PCN#	Effective Date	Issue Date
2014-08-01C-15	2015/2/1	2014/8/1
PCN Classification	Product Category	
Major	SOD-523 Package	
Subject		
Add a molding vendor		
Affected Product(s)		
As attachment		
Description of Change(s)		
In order to avoid shortage of the material, and enhance the speed of delivery, thus, we add a new vendor.		
Content of Change(s)		
Add Molding vendor--ELER-8-100HFE		
Impact(s)		
N/A		
Attachment(s)		
Reliability Teat Report.		

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website <http://www.secosgmbh.com>

Affected Product

SCS389S	SCS387S
BAT54X	SCS400S
SCS520S	SCS422S
SCS521S	BAP51W-02
SCS751S	ESD03R
SD103AX	ESD05C
SCS520S-40	ESD05R
SCS388S	ESD07R
BAS16S	ESD12R
BAS516S	ESDL05R
SCS4148S	MM5Z Series



Reliability Testing Summary Report

Date: 2014/06/30

Document No.: SH14 -06- 33

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SCS520S	100 ± 5°C, 100% VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SCS520S	150°C, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SCS520S	121°C, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SCS520S	-55°C/30min, 150°C/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SCS520S	85 ± 2°C, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SCS520S	85 ± 2°C, RH=85±5%, 1000 hrs		77	0	0	ACC
Solderability	SCS520S	245 ± 5°C, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

Judgment:

qualified unqualified

Testing Start Date: 2014.05.05 Testing End Date: 2014.06.30

Tester: Leo Hsia Approval: Peter Yang



Electrical Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
1	496.7mV	42.04V	0.369uA
2	499.0mV	43.11V	0.346uA
3	499.9mV	44.28V	0.426uA
4	500.2mV	44.72V	0.382uA
5	490.6mV	47.97V	0.327uA
6	501.7mV	44.28V	0.318uA
7	498.8mV	43.16V	0.299uA
8	491.7mV	45.04V	0.393uA
9	491.0mV	46.41V	0.416uA
10	494.9mV	40.81V	0.374uA
11	494.2mV	45.18V	0.321uA
12	485.9mV	46.27V	0.410uA
13	486.6mV	47.93V	0.376uA
14	483.2mV	48.11V	0.366uA
15	489.9mV	43.85V	0.390uA
16	494.6mV	46.51V	0.367uA
17	482.7mV	40.63V	0.415uA
18	495.9mV	42.69V	0.403uA
19	495.6mV	42.93V	0.376uA
20	483.1mV	47.18V	0.378uA
21	487.6mV	43.33V	0.423uA
22	486.3mV	45.44V	0.354uA
23	489.4mV	47.36V	0.368uA
24	496.4mV	47.79V	0.317uA
25	486.5mV	41.70V	0.297uA
26	499.3mV	42.57V	0.327uA
27	501.5mV	46.98V	0.312uA
28	493.2mV	44.22V	0.391uA
29	493.9mV	43.76V	0.372uA
30	493.3mV	47.24V	0.399uA
31	499.1mV	41.47V	0.410uA



Electrical Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
32	488.4mV	44.24V	0.416uA
33	488.7mV	47.47V	0.354uA
34	491.3mV	45.60V	0.350uA
35	500.8mV	44.90V	0.344uA
36	500.4mV	46.76V	0.393uA
37	486.5mV	46.61V	0.299uA
38	498.8mV	43.95V	0.314uA
39	486.8mV	41.20V	0.345uA
40	489.1mV	41.70V	0.376uA
41	498.9mV	43.97V	0.400uA
42	494.5mV	47.85V	0.307uA
43	496.9mV	41.90V	0.423uA
44	500.5mV	46.19V	0.422uA
45	492.8mV	44.38V	0.326uA
46	497.2mV	43.78V	0.379uA
47	490.0mV	44.93V	0.405uA
48	493.8mV	43.91V	0.375uA
49	497.0mV	47.28V	0.401uA
50	492.5mV	47.56V	0.409uA
51	489.2mV	43.63V	0.319uA
52	482.0mV	45.78V	0.400uA
53	499.1mV	46.02V	0.319uA
54	495.5mV	42.83V	0.302uA
55	495.1mV	46.74V	0.399uA
56	491.3mV	43.10V	0.305uA
57	500.8mV	41.03V	0.301uA
58	486.0mV	45.94V	0.383uA
59	493.7mV	41.57V	0.313uA
60	488.4mV	47.88V	0.349uA
61	500.4mV	40.56V	0.418uA
62	499.3mV	46.28V	0.346uA



Electrical Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
63	500.2mV	46.01V	0.423uA
64	495.4mV	47.36V	0.406uA
65	491.1mV	43.01V	0.358uA
66	490.2mV	47.54V	0.431uA
67	484.1mV	42.01V	0.426uA
68	495.0mV	48.06V	0.382uA
69	485.9mV	44.53V	0.422uA
70	484.3mV	45.10V	0.325uA
71	486.3mV	41.00V	0.366uA
72	493.6mV	45.88V	0.395uA
73	492.3mV	43.44V	0.406uA
74	482.5mV	44.59V	0.435uA
75	489.1mV	45.56V	0.353uA
76	485.8mV	44.21V	0.425uA
77	485.5mV	40.50V	0.370uA

Made By: Leo Hsia

Approval: Peter Yang



High Temperature Reverse Bias Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	493.5mV	45.72V	0.375uA	491.8mV	45.41V	0.437uA
2	485.9mV	43.87V	0.360uA	488.6mV	44.38V	0.328uA
3	498.6mV	47.41V	0.351uA	488.3mV	40.56V	0.309uA
4	487.7mV	42.58V	0.372uA	493.9mV	41.91V	0.412uA
5	494.4mV	47.35V	0.303uA	497.6mV	44.06V	0.399uA
6	481.9mV	45.45V	0.376uA	495.1mV	43.59V	0.417uA
7	488.5mV	40.82V	0.373uA	490.7mV	43.93V	0.354uA
8	494.2mV	47.84V	0.430uA	495.9mV	47.60V	0.437uA
9	500.9mV	44.37V	0.350uA	482.7mV	41.13V	0.410uA
10	485.7mV	47.22V	0.351uA	485.3mV	47.76V	0.413uA
11	492.9mV	44.67V	0.310uA	499.4mV	43.76V	0.332uA
12	497.5mV	46.80V	0.386uA	494.6mV	41.37V	0.327uA
13	486.8mV	41.61V	0.392uA	487.6mV	41.94V	0.383uA
14	485.6mV	44.60V	0.353uA	499.7mV	43.19V	0.345uA
15	499.1mV	41.00V	0.360uA	499.6mV	47.25V	0.335uA
16	491.3mV	42.07V	0.345uA	488.0mV	44.51V	0.387uA
17	501.6mV	45.91V	0.392uA	489.0mV	41.63V	0.417uA
18	483.4mV	46.01V	0.346uA	483.3mV	45.12V	0.398uA
19	484.9mV	42.32V	0.362uA	491.9mV	44.01V	0.311uA
20	496.6mV	45.06V	0.299uA	491.9mV	45.57V	0.345uA
21	488.3mV	46.96V	0.401uA	482.5mV	41.03V	0.398uA
22	484.6mV	47.59V	0.373uA	481.9mV	42.64V	0.391uA
23	493.8mV	47.85V	0.415uA	482.8mV	42.19V	0.337uA
24	495.9mV	43.42V	0.374uA	483.7mV	42.07V	0.401uA
25	483.1mV	40.49V	0.417uA	487.3mV	42.15V	0.305uA
26	483.2mV	44.06V	0.296uA	492.2mV	41.86V	0.371uA
27	492.6mV	43.82V	0.314uA	490.7mV	43.13V	0.354uA
28	501.6mV	43.67V	0.336uA	491.2mV	43.62V	0.420uA
29	483.9mV	43.77V	0.353uA	500.3mV	45.09V	0.355uA
30	497.1mV	45.35V	0.357uA	489.3mV	48.05V	0.425uA



High Temperature Reverse Bias Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	501.2mV	41.10V	0.392uA	494.3mV	47.63V	0.403uA
32	483.0mV	43.77V	0.373uA	487.7mV	46.71V	0.388uA
33	487.5mV	46.12V	0.327uA	490.8mV	46.62V	0.319uA
34	500.2mV	44.00V	0.386uA	493.6mV	41.30V	0.389uA
35	491.6mV	47.46V	0.361uA	501.0mV	47.43V	0.328uA
36	491.8mV	46.19V	0.369uA	486.3mV	41.41V	0.371uA
37	500.9mV	46.51V	0.370uA	488.9mV	45.07V	0.319uA
38	483.5mV	45.09V	0.412uA	490.6mV	45.90V	0.371uA
39	482.1mV	43.73V	0.421uA	485.2mV	44.46V	0.327uA
40	492.3mV	40.80V	0.422uA	486.0mV	43.32V	0.348uA
41	501.2mV	47.82V	0.423uA	483.1mV	41.61V	0.374uA
42	484.2mV	47.34V	0.438uA	492.2mV	42.21V	0.417uA
43	492.3mV	44.25V	0.316uA	483.1mV	41.56V	0.377uA
44	489.0mV	45.85V	0.338uA	499.1mV	47.76V	0.378uA
45	487.5mV	43.80V	0.374uA	483.9mV	43.26V	0.378uA
46	482.4mV	44.43V	0.313uA	492.7mV	40.58V	0.301uA
47	498.1mV	45.19V	0.297uA	499.3mV	47.89V	0.326uA
48	491.8mV	43.80V	0.404uA	486.7mV	42.86V	0.417uA
49	497.1mV	41.63V	0.396uA	497.9mV	44.68V	0.315uA
50	484.4mV	41.89V	0.341uA	500.3mV	47.61V	0.320uA
51	484.1mV	46.76V	0.379uA	498.9mV	43.65V	0.352uA
52	498.8mV	42.96V	0.371uA	499.8mV	42.67V	0.301uA
53	497.8mV	41.98V	0.433uA	484.2mV	47.78V	0.389uA
54	485.0mV	47.94V	0.313uA	497.9mV	47.33V	0.363uA
55	490.6mV	44.57V	0.434uA	496.2mV	46.79V	0.334uA
56	501.0mV	45.07V	0.373uA	493.4mV	46.91V	0.308uA
57	487.2mV	46.28V	0.386uA	487.0mV	45.25V	0.418uA
58	487.8mV	46.03V	0.328uA	496.4mV	46.97V	0.370uA
59	491.3mV	41.17V	0.436uA	491.4mV	45.77V	0.380uA
60	481.9mV	43.91V	0.423uA	482.0mV	44.72V	0.304uA



High Temperature Reverse Bias Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	500.3mV	44.51V	0.413uA	484.4mV	41.75V	0.376uA
62	501.7mV	47.98V	0.304uA	492.5mV	44.81V	0.388uA
63	486.1mV	46.71V	0.325uA	496.1mV	46.73V	0.298uA
64	500.9mV	45.61V	0.395uA	485.9mV	43.00V	0.357uA
65	492.6mV	45.05V	0.399uA	497.4mV	45.90V	0.407uA
66	485.3mV	41.06V	0.318uA	498.4mV	47.59V	0.302uA
67	498.5mV	44.23V	0.338uA	484.2mV	42.45V	0.433uA
68	482.9mV	45.13V	0.298uA	490.9mV	43.71V	0.368uA
69	492.5mV	44.45V	0.366uA	497.7mV	43.21V	0.418uA
70	501.4mV	47.04V	0.354uA	498.2mV	45.59V	0.374uA
71	485.1mV	47.25V	0.437uA	484.1mV	40.67V	0.330uA
72	490.4mV	47.36V	0.438uA	492.2mV	41.35V	0.352uA
73	495.4mV	41.28V	0.385uA	488.7mV	41.31V	0.381uA
74	497.1mV	40.83V	0.386uA	488.6mV	48.05V	0.401uA
75	491.6mV	43.86V	0.366uA	485.6mV	46.70V	0.331uA
76	481.8mV	44.97V	0.426uA	495.5mV	47.60V	0.438uA
77	497.4mV	41.23V	0.361uA	486.8mV	45.22V	0.305uA

Made By: Leo Hsia

Approval: Peter Yang



High Temperature Storage Life Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	485.0mV	47.61V	0.427uA	486.7mV	44.39V	0.379uA
2	482.8mV	44.83V	0.383uA	499.9mV	43.40V	0.376uA
3	499.2mV	40.59V	0.410uA	500.3mV	42.01V	0.337uA
4	490.7mV	46.04V	0.325uA	493.4mV	45.24V	0.332uA
5	482.0mV	47.30V	0.438uA	498.0mV	44.97V	0.317uA
6	491.9mV	47.46V	0.386uA	488.3mV	45.83V	0.339uA
7	489.4mV	44.51V	0.371uA	489.7mV	41.98V	0.352uA
8	500.0mV	41.33V	0.436uA	497.0mV	44.92V	0.311uA
9	500.3mV	45.06V	0.413uA	500.0mV	44.49V	0.313uA
10	486.4mV	44.36V	0.317uA	497.1mV	43.33V	0.306uA
11	487.0mV	43.24V	0.314uA	499.0mV	42.75V	0.378uA
12	494.0mV	47.82V	0.390uA	497.9mV	46.56V	0.417uA
13	495.9mV	46.52V	0.308uA	488.1mV	45.90V	0.318uA
14	483.4mV	45.24V	0.370uA	493.0mV	46.20V	0.390uA
15	496.9mV	42.09V	0.336uA	499.6mV	44.99V	0.358uA
16	501.2mV	41.87V	0.413uA	486.3mV	46.49V	0.304uA
17	494.6mV	43.39V	0.412uA	483.0mV	45.35V	0.303uA
18	498.2mV	42.61V	0.356uA	481.9mV	47.91V	0.392uA
19	484.7mV	45.89V	0.344uA	482.0mV	47.03V	0.393uA
20	490.8mV	44.86V	0.346uA	487.5mV	42.44V	0.420uA
21	492.9mV	41.68V	0.425uA	494.0mV	47.71V	0.366uA
22	491.6mV	46.09V	0.369uA	490.8mV	41.41V	0.390uA
23	490.7mV	45.08V	0.405uA	484.5mV	46.00V	0.433uA
24	494.8mV	44.30V	0.376uA	499.8mV	41.72V	0.404uA
25	497.5mV	46.06V	0.336uA	499.8mV	47.95V	0.410uA
26	491.8mV	43.07V	0.363uA	483.5mV	44.59V	0.400uA
27	491.8mV	41.61V	0.362uA	483.7mV	41.07V	0.406uA
28	499.5mV	46.83V	0.412uA	497.0mV	41.47V	0.337uA
29	488.6mV	46.20V	0.340uA	490.7mV	42.76V	0.360uA
30	483.5mV	45.62V	0.330uA	490.7mV	40.95V	0.296uA



High Temperature Storage Life Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	485.5mV	44.33V	0.353uA	492.2mV	42.18V	0.352uA
32	482.7mV	42.90V	0.435uA	490.2mV	41.68V	0.331uA
33	488.8mV	45.53V	0.432uA	500.1mV	45.33V	0.348uA
34	485.5mV	44.20V	0.298uA	484.2mV	41.12V	0.392uA
35	490.9mV	44.09V	0.429uA	483.1mV	41.23V	0.332uA
36	488.9mV	47.47V	0.427uA	501.2mV	41.51V	0.372uA
37	485.3mV	47.53V	0.346uA	492.8mV	47.19V	0.427uA
38	483.4mV	40.63V	0.320uA	484.8mV	44.06V	0.336uA
39	501.6mV	42.30V	0.409uA	482.5mV	46.13V	0.381uA
40	492.1mV	43.20V	0.408uA	495.9mV	47.15V	0.348uA
41	496.2mV	46.75V	0.394uA	497.3mV	41.94V	0.377uA
42	495.2mV	45.17V	0.405uA	482.3mV	46.61V	0.400uA
43	494.8mV	47.55V	0.426uA	495.2mV	40.77V	0.368uA
44	486.9mV	45.06V	0.411uA	491.8mV	40.62V	0.425uA
45	495.0mV	41.82V	0.317uA	494.2mV	45.62V	0.337uA
46	493.3mV	47.83V	0.415uA	501.3mV	41.19V	0.308uA
47	487.5mV	47.24V	0.311uA	486.5mV	48.05V	0.311uA
48	488.8mV	44.80V	0.309uA	497.4mV	46.02V	0.368uA
49	499.3mV	42.34V	0.320uA	491.6mV	45.09V	0.348uA
50	492.5mV	47.38V	0.310uA	490.4mV	41.09V	0.367uA
51	497.5mV	46.89V	0.392uA	498.2mV	46.05V	0.323uA
52	482.0mV	43.11V	0.424uA	497.3mV	42.49V	0.374uA
53	484.0mV	41.38V	0.429uA	487.6mV	44.13V	0.377uA
54	487.6mV	45.91V	0.337uA	484.0mV	41.47V	0.374uA
55	495.3mV	46.48V	0.363uA	499.7mV	47.86V	0.423uA
56	488.6mV	41.85V	0.434uA	494.4mV	41.74V	0.376uA
57	493.1mV	44.73V	0.414uA	498.3mV	43.59V	0.433uA
58	482.9mV	44.50V	0.297uA	484.7mV	43.10V	0.438uA
59	485.4mV	42.84V	0.329uA	485.9mV	46.02V	0.425uA
60	499.7mV	41.78V	0.413uA	488.9mV	46.01V	0.396uA



High Temperature Storage Life Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	493.0mV	47.93V	0.331uA	490.8mV	47.77V	0.404uA
62	482.0mV	43.88V	0.334uA	488.9mV	44.59V	0.345uA
63	496.0mV	40.80V	0.335uA	489.5mV	46.62V	0.382uA
64	498.7mV	45.30V	0.372uA	500.5mV	45.45V	0.297uA
65	482.1mV	46.56V	0.312uA	488.4mV	46.48V	0.330uA
66	483.0mV	47.06V	0.369uA	501.0mV	44.70V	0.406uA
67	487.6mV	45.91V	0.401uA	501.2mV	40.96V	0.304uA
68	494.4mV	40.93V	0.358uA	482.6mV	41.26V	0.417uA
69	489.5mV	44.82V	0.406uA	490.8mV	43.58V	0.319uA
70	494.5mV	41.96V	0.332uA	491.0mV	43.43V	0.326uA
71	488.4mV	46.62V	0.383uA	481.7mV	46.35V	0.410uA
72	500.4mV	41.66V	0.416uA	481.9mV	47.37V	0.356uA
73	494.0mV	43.37V	0.404uA	483.6mV	48.07V	0.337uA
74	497.6mV	45.50V	0.350uA	499.1mV	41.89V	0.321uA
75	494.9mV	41.67V	0.406uA	497.5mV	42.62V	0.344uA
76	500.8mV	40.57V	0.413uA	487.2mV	42.54V	0.409uA
77	490.7mV	41.47V	0.326uA	481.9mV	44.53V	0.331uA

Made By: Leo Hsia

Approval: Peter Yang



SeCoS Corporation

Pressure Cooker Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	486.5mV	42.80V	0.414uA	484.4mV	45.07V	0.410uA
2	498.0mV	45.94V	0.419uA	496.8mV	43.90V	0.330uA
3	485.1mV	45.78V	0.301uA	493.3mV	41.40V	0.307uA
4	492.4mV	47.10V	0.404uA	497.6mV	40.88V	0.373uA
5	493.5mV	47.17V	0.303uA	482.5mV	45.64V	0.307uA
6	484.4mV	40.90V	0.312uA	494.5mV	41.41V	0.326uA
7	484.7mV	46.23V	0.353uA	490.5mV	45.56V	0.415uA
8	482.1mV	45.12V	0.297uA	488.8mV	40.55V	0.335uA
9	495.2mV	44.90V	0.307uA	499.8mV	46.11V	0.402uA
10	492.8mV	45.17V	0.351uA	484.9mV	45.82V	0.419uA
11	491.3mV	47.06V	0.333uA	483.9mV	42.64V	0.399uA
12	483.0mV	46.99V	0.304uA	482.0mV	47.39V	0.386uA
13	486.4mV	42.24V	0.394uA	493.1mV	43.40V	0.315uA
14	487.9mV	47.24V	0.404uA	489.9mV	44.82V	0.423uA
15	484.3mV	46.45V	0.299uA	498.0mV	47.52V	0.314uA
16	484.4mV	45.20V	0.324uA	482.3mV	46.58V	0.360uA
17	482.2mV	47.66V	0.402uA	497.5mV	41.98V	0.344uA
18	500.6mV	47.46V	0.339uA	485.4mV	48.00V	0.428uA
19	487.9mV	40.52V	0.434uA	496.6mV	45.12V	0.413uA
20	496.8mV	47.81V	0.358uA	487.9mV	40.70V	0.302uA
21	496.2mV	46.14V	0.388uA	491.7mV	43.58V	0.386uA
22	486.6mV	41.05V	0.391uA	492.3mV	44.05V	0.429uA
23	483.4mV	44.95V	0.421uA	495.7mV	47.39V	0.298uA
24	492.7mV	42.02V	0.381uA	488.3mV	44.46V	0.329uA
25	483.9mV	40.74V	0.332uA	494.2mV	42.48V	0.331uA
26	490.3mV	46.00V	0.326uA	499.4mV	41.23V	0.396uA
27	491.9mV	46.18V	0.300uA	493.1mV	42.83V	0.384uA
28	483.0mV	47.41V	0.301uA	499.8mV	42.26V	0.408uA
29	481.7mV	46.28V	0.427uA	501.5mV	40.65V	0.358uA
30	483.3mV	45.61V	0.352uA	491.0mV	41.54V	0.333uA



SeCoS Corporation

Pressure Cooker Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	495.6mV	46.48V	0.378uA	494.4mV	44.90V	0.372uA
32	491.3mV	40.74V	0.321uA	490.1mV	43.72V	0.333uA
33	492.1mV	41.69V	0.345uA	485.4mV	46.46V	0.315uA
34	490.3mV	47.49V	0.374uA	488.1mV	42.37V	0.400uA
35	486.5mV	42.66V	0.377uA	490.3mV	43.45V	0.359uA
36	489.0mV	40.75V	0.369uA	496.6mV	47.61V	0.370uA
37	493.7mV	43.37V	0.388uA	499.8mV	42.24V	0.329uA
38	491.2mV	47.63V	0.363uA	489.3mV	45.56V	0.323uA
39	487.5mV	41.33V	0.382uA	501.1mV	42.82V	0.308uA
40	495.1mV	45.89V	0.365uA	499.0mV	41.45V	0.319uA
41	498.5mV	46.31V	0.339uA	487.6mV	40.50V	0.435uA
42	492.4mV	45.54V	0.313uA	484.9mV	47.06V	0.370uA
43	488.4mV	44.48V	0.325uA	482.0mV	45.42V	0.433uA
44	490.4mV	45.32V	0.330uA	495.2mV	43.98V	0.408uA
45	487.5mV	40.54V	0.351uA	493.0mV	40.81V	0.379uA
46	483.5mV	41.00V	0.356uA	493.0mV	44.12V	0.431uA
47	493.6mV	47.95V	0.380uA	483.1mV	42.24V	0.311uA
48	499.8mV	43.56V	0.373uA	487.4mV	45.86V	0.322uA
49	499.8mV	40.61V	0.337uA	485.6mV	46.43V	0.390uA
50	490.0mV	47.20V	0.355uA	493.2mV	45.30V	0.304uA
51	491.5mV	44.28V	0.309uA	497.1mV	43.94V	0.419uA
52	494.4mV	47.23V	0.361uA	499.5mV	44.24V	0.340uA
53	493.5mV	41.71V	0.390uA	487.4mV	47.37V	0.319uA
54	489.1mV	45.05V	0.380uA	493.3mV	47.75V	0.374uA
55	497.0mV	41.27V	0.437uA	493.3mV	44.11V	0.400uA
56	499.8mV	47.39V	0.343uA	498.7mV	44.16V	0.327uA
57	485.3mV	46.28V	0.392uA	498.7mV	46.94V	0.367uA
58	488.0mV	43.15V	0.413uA	495.4mV	42.04V	0.404uA
59	485.4mV	47.49V	0.405uA	489.5mV	45.58V	0.334uA
60	490.0mV	41.17V	0.381uA	482.9mV	47.45V	0.353uA



SeCoS Corporation

Pressure Cooker Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	492.8mV	45.13V	0.397uA	492.1mV	43.52V	0.418uA
62	497.6mV	45.58V	0.366uA	484.7mV	44.52V	0.399uA
63	497.2mV	44.79V	0.301uA	499.9mV	47.24V	0.436uA
64	484.4mV	44.55V	0.331uA	487.1mV	41.23V	0.411uA
65	486.0mV	43.00V	0.409uA	498.0mV	47.96V	0.349uA
66	481.7mV	41.22V	0.335uA	490.8mV	44.91V	0.349uA
67	490.6mV	42.52V	0.348uA	498.0mV	43.74V	0.383uA
68	489.1mV	46.97V	0.384uA	489.3mV	41.10V	0.404uA
69	495.6mV	46.35V	0.328uA	493.7mV	46.78V	0.354uA
70	499.9mV	46.34V	0.308uA	484.1mV	43.34V	0.399uA
71	499.0mV	46.51V	0.423uA	500.9mV	43.61V	0.413uA
72	493.6mV	42.36V	0.304uA	487.1mV	44.20V	0.417uA
73	499.5mV	42.32V	0.373uA	496.6mV	44.91V	0.435uA
74	482.0mV	40.58V	0.412uA	495.8mV	45.06V	0.320uA
75	501.5mV	43.18V	0.305uA	487.1mV	42.83V	0.392uA
76	490.5mV	42.80V	0.315uA	487.8mV	43.61V	0.331uA
77	491.6mV	40.62V	0.310uA	489.0mV	43.64V	0.394uA

Made By: Leo Hsia

Approval: Peter Yang



SeCoS Corporation

Temperature Cycle Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	501.3mV	47.68V	0.419uA	487.7mV	42.32V	0.417uA
2	482.9mV	46.94V	0.431uA	486.0mV	47.37V	0.343uA
3	496.3mV	47.54V	0.399uA	484.0mV	44.50V	0.360uA
4	492.3mV	47.31V	0.406uA	491.1mV	45.63V	0.339uA
5	491.7mV	41.62V	0.352uA	493.6mV	42.62V	0.315uA
6	499.8mV	48.05V	0.417uA	492.2mV	42.39V	0.407uA
7	497.1mV	41.96V	0.326uA	484.4mV	41.74V	0.355uA
8	481.8mV	45.79V	0.377uA	482.3mV	44.92V	0.356uA
9	500.8mV	45.72V	0.398uA	488.0mV	44.44V	0.366uA
10	492.5mV	46.60V	0.419uA	492.4mV	44.84V	0.428uA
11	494.9mV	47.55V	0.415uA	484.8mV	43.19V	0.346uA
12	490.3mV	47.74V	0.369uA	498.8mV	46.28V	0.358uA
13	485.7mV	43.56V	0.424uA	484.3mV	44.83V	0.314uA
14	492.6mV	41.31V	0.402uA	490.6mV	46.49V	0.343uA
15	484.9mV	43.11V	0.305uA	498.7mV	42.64V	0.388uA
16	492.8mV	46.57V	0.349uA	501.6mV	41.71V	0.370uA
17	494.4mV	43.45V	0.416uA	483.0mV	44.04V	0.306uA
18	498.3mV	47.21V	0.408uA	482.0mV	45.54V	0.375uA
19	496.4mV	41.87V	0.357uA	494.3mV	48.06V	0.424uA
20	485.8mV	43.36V	0.379uA	492.8mV	40.66V	0.367uA
21	500.4mV	43.13V	0.421uA	500.0mV	40.75V	0.383uA
22	482.2mV	43.43V	0.305uA	495.2mV	45.73V	0.334uA
23	482.5mV	41.16V	0.395uA	483.0mV	44.90V	0.300uA
24	495.1mV	41.94V	0.345uA	492.5mV	42.23V	0.385uA
25	498.9mV	43.25V	0.404uA	493.7mV	42.37V	0.407uA
26	482.6mV	40.99V	0.296uA	492.3mV	42.68V	0.424uA
27	489.9mV	44.91V	0.379uA	488.8mV	47.89V	0.365uA
28	499.6mV	45.74V	0.299uA	485.3mV	47.42V	0.365uA
29	485.7mV	41.28V	0.325uA	493.9mV	43.21V	0.303uA
30	486.9mV	41.94V	0.349uA	486.9mV	46.76V	0.311uA



SeCoS Corporation

Temperature Cycle Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	485.7mV	42.20V	0.411uA	493.2mV	43.08V	0.393uA
32	485.7mV	45.72V	0.341uA	486.7mV	46.36V	0.370uA
33	495.9mV	47.09V	0.415uA	484.3mV	44.28V	0.386uA
34	484.8mV	40.70V	0.431uA	484.7mV	41.21V	0.313uA
35	489.5mV	41.37V	0.349uA	483.9mV	46.89V	0.404uA
36	498.7mV	44.55V	0.417uA	485.7mV	47.17V	0.353uA
37	496.0mV	46.64V	0.346uA	494.0mV	42.97V	0.339uA
38	483.5mV	41.64V	0.401uA	499.6mV	42.89V	0.401uA
39	487.7mV	46.39V	0.343uA	491.8mV	42.12V	0.318uA
40	494.9mV	41.61V	0.413uA	486.4mV	46.26V	0.302uA
41	491.8mV	40.73V	0.344uA	490.7mV	47.33V	0.299uA
42	483.9mV	43.24V	0.385uA	491.9mV	44.02V	0.423uA
43	486.4mV	47.53V	0.308uA	482.6mV	43.89V	0.409uA
44	501.2mV	42.34V	0.312uA	493.4mV	46.73V	0.367uA
45	500.1mV	45.92V	0.426uA	497.5mV	46.48V	0.405uA
46	483.3mV	42.17V	0.424uA	501.1mV	45.47V	0.360uA
47	488.8mV	45.22V	0.437uA	491.6mV	47.56V	0.407uA
48	482.7mV	47.88V	0.341uA	489.1mV	44.11V	0.397uA
49	482.5mV	47.43V	0.342uA	497.0mV	44.03V	0.318uA
50	484.0mV	41.96V	0.341uA	483.6mV	46.26V	0.329uA
51	498.6mV	42.03V	0.332uA	484.9mV	46.03V	0.427uA
52	488.3mV	41.21V	0.417uA	485.4mV	46.78V	0.435uA
53	495.0mV	47.48V	0.438uA	495.2mV	41.29V	0.434uA
54	497.3mV	45.89V	0.364uA	487.9mV	44.77V	0.387uA
55	488.5mV	44.71V	0.406uA	491.7mV	44.40V	0.423uA
56	486.4mV	47.94V	0.421uA	482.4mV	41.77V	0.406uA
57	498.2mV	46.41V	0.386uA	497.0mV	47.06V	0.438uA
58	498.6mV	42.74V	0.353uA	481.7mV	45.79V	0.387uA
59	498.6mV	41.27V	0.382uA	482.6mV	41.25V	0.308uA
60	499.5mV	46.35V	0.320uA	499.4mV	46.15V	0.391uA



SeCoS Corporation

Temperature Cycle Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	501.4mV	40.60V	0.427uA	482.1mV	47.38V	0.385uA
62	500.2mV	43.61V	0.408uA	491.3mV	41.77V	0.406uA
63	496.9mV	45.95V	0.378uA	483.9mV	46.92V	0.387uA
64	498.4mV	41.18V	0.414uA	485.3mV	43.89V	0.351uA
65	495.7mV	43.84V	0.361uA	494.2mV	45.77V	0.353uA
66	494.1mV	47.49V	0.384uA	489.2mV	44.02V	0.389uA
67	489.9mV	45.38V	0.397uA	486.2mV	42.97V	0.383uA
68	500.1mV	47.03V	0.402uA	484.3mV	47.38V	0.375uA
69	501.5mV	43.45V	0.380uA	486.2mV	42.17V	0.321uA
70	490.0mV	45.66V	0.355uA	486.7mV	42.45V	0.410uA
71	492.0mV	44.48V	0.302uA	483.1mV	41.95V	0.394uA
72	488.0mV	43.00V	0.321uA	501.3mV	46.76V	0.394uA
73	495.1mV	42.64V	0.313uA	499.3mV	45.01V	0.431uA
74	493.8mV	40.65V	0.407uA	500.5mV	44.44V	0.419uA
75	496.7mV	41.14V	0.429uA	488.9mV	44.11V	0.376uA
76	501.5mV	43.03V	0.387uA	482.9mV	43.39V	0.406uA
77	486.6mV	42.22V	0.365uA	493.3mV	42.66V	0.411uA

Made By: Leo Hsia

Approval: Peter Yang



High Temperature High Humidity Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	486.3mV	42.27V	0.355uA	492.1mV	46.61V	0.310uA
2	489.7mV	40.61V	0.344uA	494.7mV	45.56V	0.438uA
3	495.5mV	44.12V	0.407uA	497.2mV	42.88V	0.336uA
4	499.1mV	44.77V	0.403uA	486.6mV	43.31V	0.360uA
5	483.4mV	43.32V	0.330uA	486.0mV	44.10V	0.363uA
6	498.9mV	47.10V	0.400uA	498.3mV	44.88V	0.334uA
7	493.3mV	43.06V	0.362uA	492.8mV	43.04V	0.371uA
8	498.6mV	41.18V	0.430uA	487.9mV	41.63V	0.318uA
9	495.9mV	46.62V	0.434uA	495.8mV	46.03V	0.375uA
10	491.3mV	42.46V	0.399uA	500.5mV	45.01V	0.320uA
11	485.8mV	45.10V	0.432uA	484.3mV	41.82V	0.327uA
12	486.6mV	42.83V	0.359uA	488.2mV	43.28V	0.358uA
13	494.4mV	47.70V	0.327uA	491.4mV	46.06V	0.300uA
14	498.7mV	46.36V	0.318uA	488.0mV	47.03V	0.364uA
15	488.3mV	48.09V	0.433uA	489.8mV	46.47V	0.415uA
16	499.5mV	45.58V	0.403uA	494.6mV	42.97V	0.318uA
17	489.4mV	45.54V	0.435uA	493.5mV	46.95V	0.296uA
18	483.5mV	46.28V	0.361uA	497.5mV	42.52V	0.308uA
19	490.6mV	47.49V	0.389uA	485.4mV	44.93V	0.311uA
20	483.1mV	45.75V	0.369uA	491.2mV	47.13V	0.382uA
21	481.8mV	42.43V	0.301uA	491.0mV	43.83V	0.335uA
22	482.2mV	45.85V	0.339uA	491.0mV	44.33V	0.412uA
23	499.2mV	47.53V	0.322uA	495.9mV	42.56V	0.351uA
24	495.6mV	40.68V	0.323uA	494.9mV	47.18V	0.364uA
25	498.3mV	46.25V	0.421uA	483.5mV	45.42V	0.406uA
26	487.8mV	43.03V	0.349uA	493.4mV	46.58V	0.391uA
27	487.7mV	42.64V	0.400uA	498.4mV	46.83V	0.422uA
28	498.7mV	41.87V	0.392uA	491.5mV	47.94V	0.423uA
29	495.7mV	46.40V	0.391uA	491.3mV	42.97V	0.368uA
30	485.7mV	47.66V	0.433uA	497.0mV	43.83V	0.351uA



High Temperature High Humidity Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	489.4mV	43.47V	0.376uA	496.0mV	42.91V	0.430uA
32	495.5mV	44.91V	0.390uA	488.9mV	43.51V	0.420uA
33	497.4mV	45.00V	0.401uA	487.0mV	41.05V	0.382uA
34	487.0mV	45.86V	0.381uA	495.5mV	43.56V	0.353uA
35	499.6mV	46.26V	0.366uA	495.4mV	41.31V	0.386uA
36	485.2mV	44.50V	0.403uA	501.2mV	45.61V	0.351uA
37	500.0mV	46.31V	0.437uA	499.5mV	43.26V	0.337uA
38	495.1mV	42.38V	0.376uA	486.2mV	47.16V	0.370uA
39	490.9mV	40.75V	0.393uA	491.5mV	40.59V	0.362uA
40	493.8mV	46.37V	0.390uA	487.5mV	45.15V	0.436uA
41	495.1mV	43.82V	0.423uA	483.6mV	40.97V	0.397uA
42	490.4mV	41.68V	0.356uA	486.1mV	46.39V	0.402uA
43	487.5mV	41.10V	0.356uA	490.8mV	44.63V	0.419uA
44	488.6mV	47.08V	0.371uA	487.3mV	43.87V	0.302uA
45	499.7mV	40.50V	0.368uA	485.4mV	41.32V	0.427uA
46	494.1mV	40.93V	0.317uA	494.3mV	41.67V	0.392uA
47	487.3mV	41.90V	0.427uA	498.1mV	47.94V	0.319uA
48	497.8mV	47.07V	0.313uA	497.1mV	46.06V	0.329uA
49	495.2mV	42.14V	0.360uA	485.2mV	45.90V	0.298uA
50	490.0mV	41.80V	0.398uA	496.7mV	46.15V	0.335uA
51	489.0mV	45.33V	0.431uA	481.8mV	42.87V	0.307uA
52	496.7mV	40.74V	0.357uA	488.9mV	43.53V	0.313uA
53	486.6mV	40.77V	0.367uA	491.9mV	47.41V	0.354uA
54	486.8mV	41.57V	0.330uA	488.8mV	42.25V	0.369uA
55	486.5mV	46.29V	0.330uA	499.3mV	46.58V	0.369uA
56	487.8mV	41.85V	0.371uA	497.0mV	40.84V	0.377uA
57	500.1mV	40.60V	0.399uA	494.7mV	44.33V	0.329uA
58	492.5mV	46.69V	0.352uA	483.1mV	46.22V	0.361uA
59	495.6mV	43.24V	0.307uA	489.8mV	42.24V	0.369uA
60	482.7mV	42.88V	0.340uA	490.7mV	41.96V	0.342uA



High Temperature High Humidity Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	488.2mV	45.60V	0.431uA	490.3mV	46.74V	0.396uA
62	497.2mV	47.90V	0.327uA	492.9mV	42.76V	0.332uA
63	500.9mV	42.04V	0.360uA	489.6mV	43.09V	0.316uA
64	496.7mV	44.08V	0.390uA	484.7mV	46.88V	0.325uA
65	498.3mV	47.40V	0.388uA	488.1mV	45.54V	0.341uA
66	488.5mV	45.48V	0.354uA	490.5mV	45.58V	0.437uA
67	495.3mV	45.59V	0.316uA	498.0mV	42.62V	0.437uA
68	486.4mV	45.72V	0.340uA	497.5mV	46.68V	0.423uA
69	497.0mV	43.57V	0.320uA	492.2mV	45.86V	0.369uA
70	493.2mV	47.52V	0.302uA	486.4mV	47.14V	0.327uA
71	490.5mV	43.69V	0.374uA	498.3mV	41.00V	0.398uA
72	486.9mV	43.43V	0.329uA	500.7mV	44.81V	0.419uA
73	492.0mV	44.17V	0.307uA	501.2mV	40.78V	0.325uA
74	487.7mV	41.98V	0.341uA	500.5mV	41.33V	0.316uA
75	491.6mV	40.70V	0.347uA	486.3mV	44.48V	0.323uA
76	484.9mV	47.29V	0.429uA	481.9mV	41.96V	0.358uA
77	496.8mV	43.76V	0.439uA	481.7mV	45.12V	0.334uA

Made By: Leo Hsia

Approval: Peter Yang



High Temper High Humidity Reverse Bies Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	493.8mV	43.33V	0.375uA	497.4mV	44.89V	0.364uA
2	495.5mV	48.01V	0.375uA	496.1mV	44.01V	0.311uA
3	482.6mV	46.06V	0.352uA	496.3mV	45.05V	0.434uA
4	490.0mV	41.88V	0.355uA	497.1mV	47.60V	0.299uA
5	487.0mV	45.36V	0.367uA	498.8mV	45.29V	0.419uA
6	487.5mV	44.33V	0.347uA	490.4mV	40.53V	0.435uA
7	482.5mV	47.14V	0.396uA	488.0mV	46.14V	0.385uA
8	488.8mV	44.32V	0.393uA	482.7mV	44.18V	0.347uA
9	489.4mV	43.81V	0.412uA	494.7mV	44.12V	0.368uA
10	485.2mV	42.02V	0.423uA	497.9mV	45.42V	0.375uA
11	497.7mV	42.62V	0.353uA	483.9mV	44.61V	0.432uA
12	499.4mV	42.56V	0.319uA	493.9mV	42.26V	0.377uA
13	484.3mV	46.24V	0.398uA	499.2mV	45.89V	0.417uA
14	492.6mV	41.37V	0.418uA	498.0mV	44.07V	0.324uA
15	492.7mV	43.09V	0.425uA	487.9mV	47.67V	0.395uA
16	497.2mV	40.52V	0.301uA	494.9mV	42.61V	0.347uA
17	481.8mV	42.48V	0.331uA	488.7mV	46.65V	0.401uA
18	497.0mV	43.14V	0.298uA	499.3mV	43.97V	0.323uA
19	488.3mV	42.92V	0.389uA	487.1mV	44.70V	0.428uA
20	495.7mV	47.87V	0.392uA	487.9mV	47.17V	0.374uA
21	489.0mV	44.19V	0.422uA	486.6mV	42.44V	0.421uA
22	487.8mV	44.49V	0.322uA	493.0mV	42.58V	0.410uA
23	484.2mV	45.31V	0.371uA	484.0mV	41.20V	0.319uA
24	487.9mV	44.92V	0.346uA	493.9mV	45.07V	0.372uA
25	500.7mV	47.21V	0.393uA	499.8mV	45.57V	0.408uA
26	486.4mV	46.11V	0.333uA	488.2mV	47.56V	0.309uA
27	487.5mV	41.64V	0.408uA	483.3mV	41.24V	0.436uA
28	492.6mV	46.91V	0.329uA	490.8mV	45.09V	0.313uA
29	489.0mV	42.08V	0.429uA	498.5mV	41.23V	0.300uA
30	498.2mV	43.73V	0.314uA	493.9mV	41.12V	0.430uA



High Temper High Humidity Reverse Bies Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	497.3mV	45.05V	0.429uA	491.3mV	45.07V	0.394uA
32	482.5mV	43.44V	0.315uA	499.3mV	47.36V	0.371uA
33	482.0mV	47.44V	0.365uA	486.6mV	41.10V	0.375uA
34	495.9mV	43.15V	0.348uA	491.7mV	44.14V	0.327uA
35	488.7mV	41.14V	0.341uA	492.3mV	46.61V	0.416uA
36	483.5mV	43.94V	0.320uA	487.6mV	41.18V	0.323uA
37	485.8mV	44.06V	0.328uA	501.6mV	46.94V	0.322uA
38	489.7mV	42.99V	0.333uA	500.4mV	42.90V	0.312uA
39	496.6mV	46.27V	0.308uA	484.3mV	47.87V	0.301uA
40	481.8mV	47.50V	0.347uA	491.3mV	41.50V	0.299uA
41	489.4mV	43.32V	0.374uA	483.0mV	47.52V	0.320uA
42	501.2mV	40.58V	0.377uA	482.1mV	43.14V	0.350uA
43	496.4mV	43.49V	0.383uA	495.2mV	42.04V	0.395uA
44	483.9mV	42.39V	0.334uA	497.8mV	40.87V	0.305uA
45	490.0mV	47.63V	0.407uA	483.0mV	43.37V	0.432uA
46	487.1mV	43.35V	0.349uA	492.7mV	42.83V	0.385uA
47	501.7mV	47.01V	0.430uA	490.5mV	41.53V	0.364uA
48	494.4mV	44.82V	0.342uA	492.9mV	43.32V	0.353uA
49	494.2mV	47.51V	0.378uA	482.9mV	47.45V	0.404uA
50	488.8mV	42.84V	0.411uA	484.8mV	41.16V	0.331uA
51	491.2mV	41.19V	0.321uA	487.3mV	43.43V	0.305uA
52	484.4mV	42.66V	0.427uA	497.1mV	43.03V	0.360uA
53	494.3mV	43.31V	0.389uA	485.8mV	44.78V	0.370uA
54	494.5mV	41.96V	0.404uA	501.0mV	42.18V	0.302uA
55	485.3mV	42.02V	0.338uA	487.6mV	44.82V	0.360uA
56	490.8mV	45.05V	0.330uA	495.3mV	44.18V	0.330uA
57	482.1mV	46.10V	0.350uA	491.0mV	46.95V	0.300uA
58	496.5mV	43.30V	0.394uA	490.7mV	45.72V	0.391uA
59	487.8mV	40.53V	0.424uA	493.8mV	47.78V	0.359uA
60	497.0mV	43.35V	0.423uA	489.3mV	41.24V	0.422uA



High Temper High Humidity Reverse Bies Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	492.2mV	41.55V	0.355uA	484.0mV	42.42V	0.422uA
62	496.1mV	45.34V	0.317uA	499.5mV	43.15V	0.363uA
63	496.2mV	40.81V	0.315uA	499.3mV	46.98V	0.392uA
64	497.4mV	47.43V	0.430uA	485.4mV	43.12V	0.405uA
65	487.1mV	44.34V	0.321uA	492.3mV	45.47V	0.301uA
66	494.5mV	42.39V	0.358uA	484.7mV	47.49V	0.398uA
67	498.5mV	40.80V	0.324uA	494.5mV	44.96V	0.400uA
68	482.2mV	42.30V	0.355uA	484.4mV	44.07V	0.399uA
69	494.4mV	44.53V	0.321uA	487.3mV	47.94V	0.377uA
70	490.4mV	42.05V	0.412uA	484.8mV	41.01V	0.304uA
71	482.1mV	45.61V	0.316uA	495.6mV	41.95V	0.394uA
72	492.9mV	41.83V	0.433uA	493.0mV	41.19V	0.405uA
73	495.8mV	41.67V	0.356uA	493.7mV	44.15V	0.428uA
74	483.7mV	41.80V	0.364uA	483.6mV	43.17V	0.409uA
75	488.0mV	47.34V	0.351uA	497.2mV	41.05V	0.408uA
76	501.1mV	47.06V	0.320uA	490.4mV	40.63V	0.318uA
77	482.4mV	47.29V	0.380uA	490.1mV	44.67V	0.374uA

Made By: Leo Hsia

Approval: Peter Yang



SeCoS Corporation

Solderability Test Data

Report No : T140630-033

Part No : SCS520S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<600mV@IF=1A, VB>30V@I=1mA, IR<1uA@VR=10V

Test Condition: 245°C ± 5°C, 5Sec

Test Date: 2014.06.28 ~ 2014.06.28

Test Standard : JESD22 STANDER Method-B102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	490.5mV	41.36V	0.401uA	491.8mV	44.17V	0.413uA
2	495.0mV	44.19V	0.405uA	487.3mV	41.97V	0.420uA
3	485.9mV	40.76V	0.303uA	498.6mV	45.21V	0.343uA
4	492.4mV	45.37V	0.356uA	498.3mV	45.64V	0.387uA
5	491.8mV	42.22V	0.389uA	494.9mV	43.96V	0.404uA
6	499.5mV	41.38V	0.374uA	484.8mV	41.54V	0.376uA
7	484.7mV	46.91V	0.398uA	494.2mV	43.62V	0.426uA
8	500.5mV	47.48V	0.343uA	492.3mV	41.80V	0.337uA
9	482.6mV	45.59V	0.317uA	494.6mV	42.18V	0.368uA
10	482.4mV	43.45V	0.343uA	493.8mV	46.54V	0.344uA

Made By: Leo Hsia

Approval: Peter Yang